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# Methods for noise calculation of active devices

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For more information



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# Overview

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- Simulation of noisy n-ports
- Separation of the noise sources
- FET example
- Application example
- Conclusion

# Noisy 2-ports

Transformation matrix

$$[T]^{(y \rightarrow a)} = \begin{bmatrix} 0 & -\frac{1}{y_{21}} \\ 1 & -\frac{y_{11}}{y_{21}} \end{bmatrix}$$

Noise matrix

$$\begin{bmatrix} v_i^{(a)} \\ i_o^{(a)} \end{bmatrix} = [T]^{(y \rightarrow a)} \begin{bmatrix} i_i^{(y)} \\ i_o^{(y)} \end{bmatrix}$$

input  
output

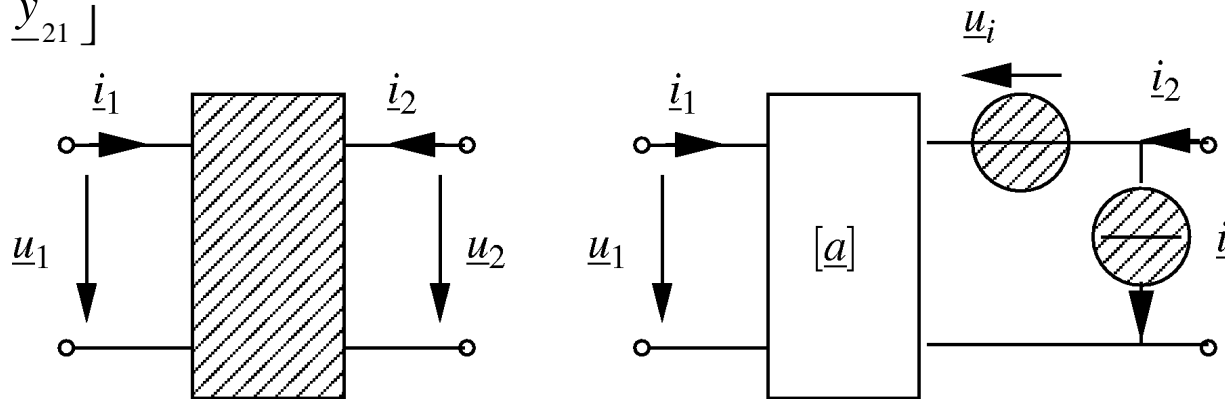


Fig.: Transformation of noise sources.

Correlation matrix, calculation of noise power

$$[C]^{(a)} = \frac{1}{4kT\Delta f} \begin{pmatrix} \begin{bmatrix} v_i \\ i_i \end{bmatrix} \begin{bmatrix} v_i^* & i_i^* \end{bmatrix} \end{pmatrix}$$

# Separation of noise sources

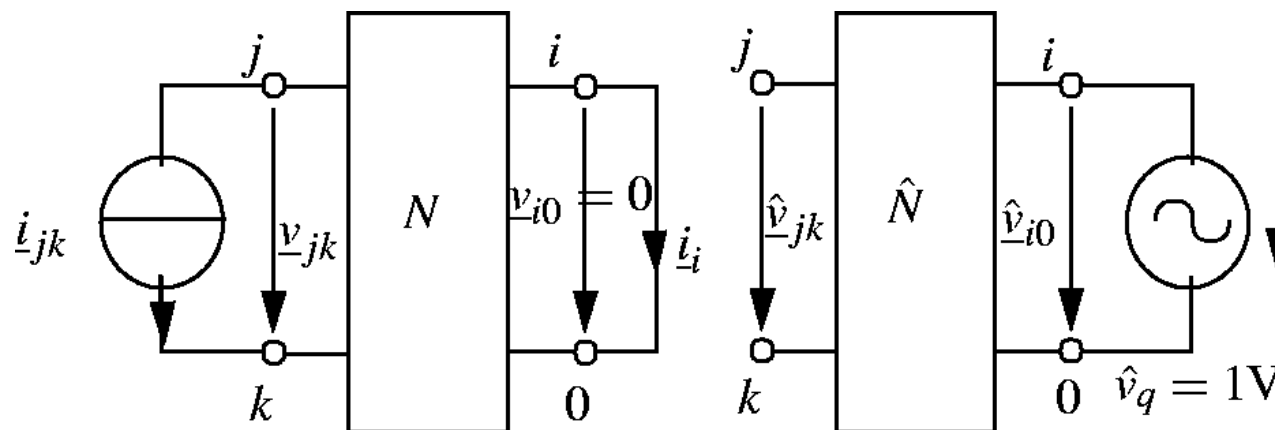


Fig.: Calculation of transformation functions.

Network N  
Y-matrix

Adjuncted network  
Transposed Y-matrix

Current transformation function

$$\alpha_{i,jk} = \frac{i_i}{i_{jk}} = -\frac{\hat{v}_{jk}}{\hat{v}_q}$$

# FET example

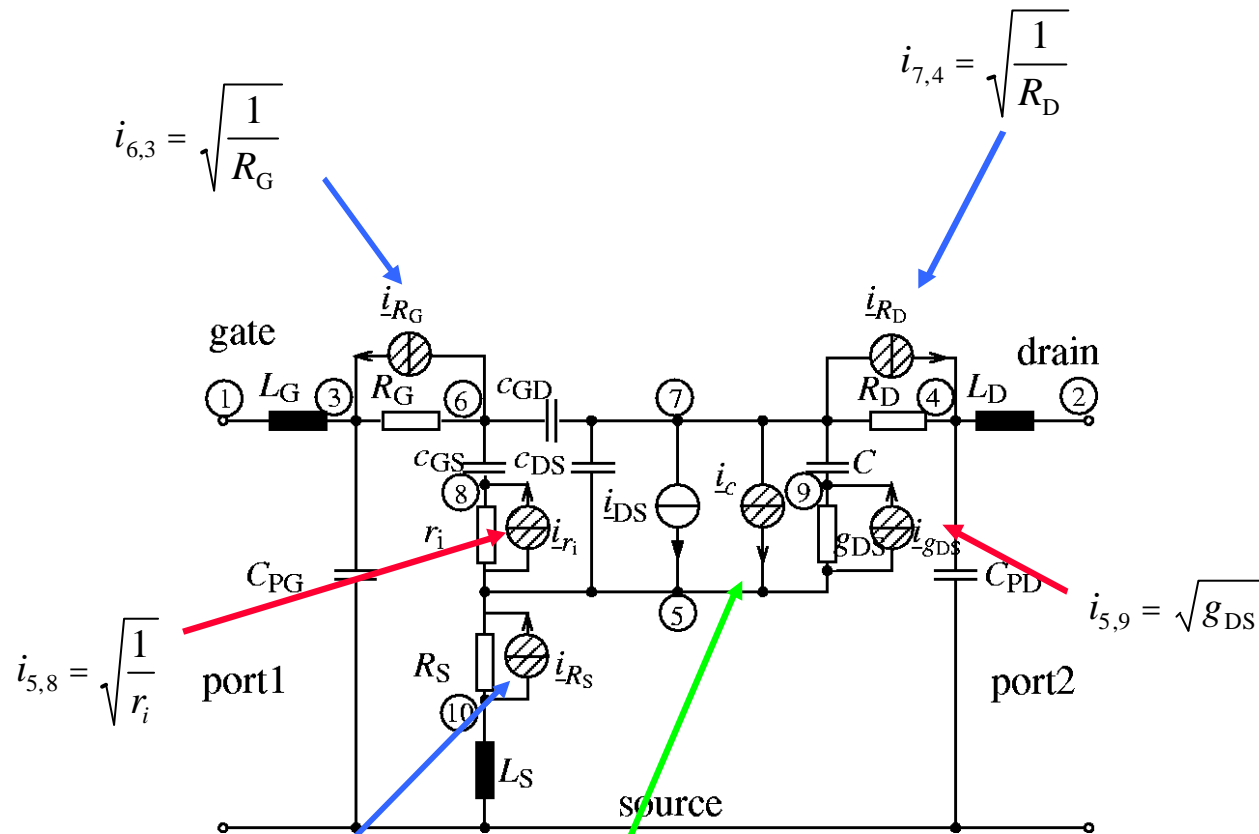


Fig.: TOPAS equivalent circuit.

Noise current matrix

$$[i_N] = \sqrt{4kT\Delta f} \cdot \begin{pmatrix} 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 & 0 & 0 & 0 & i_{5,8} & i_{5,9} & 0 \\ 0 & 0 & i_{6,3} & 0 & 0 & 0 & 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & i_{7,4} & i_{7,5} & 0 & 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 & 0 \\ 0 & 0 & 0 & 0 & i_{10,5} & 0 & 0 & 0 & 0 & 0 \end{pmatrix}$$

Channel noise

$$g_{ic} = \frac{T_{sim}}{T_0} \frac{2}{3} g_m + k_f \frac{I_c^{af}}{f^b 4kT_0}$$

1/f-noise

# Tellegen Theorem 1

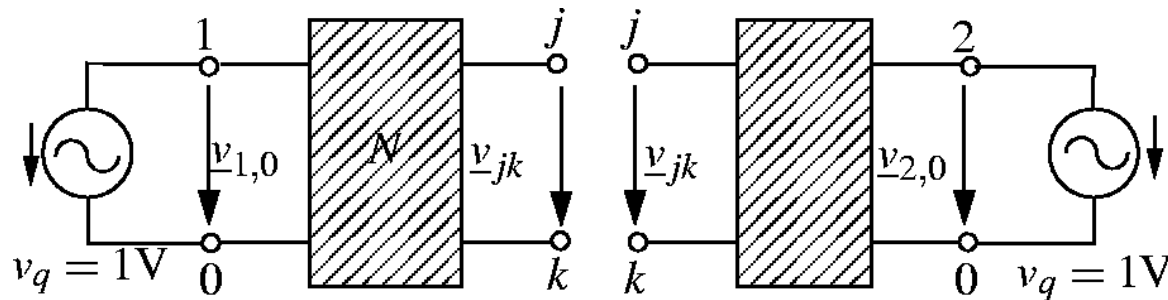
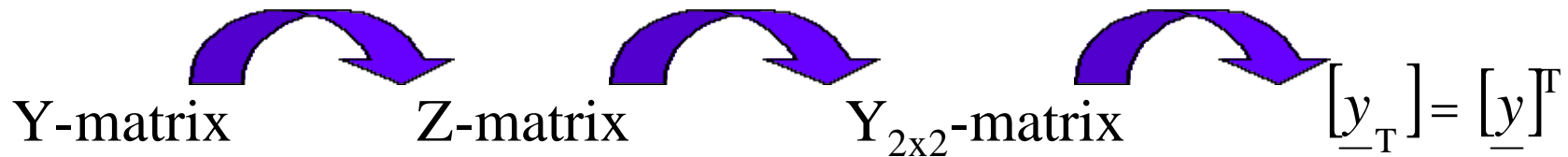


Fig.: Tellegen theorem for noisy circuits.

Adjuncted network for calculating transformation functions

$$i_{Q_1} = \frac{v_q}{\underline{y}_{T,2 \times 2,1,1}} \quad \text{and} \quad i_{Q_2} = \frac{v_q}{\underline{y}_{T,2 \times 2,2,2}}$$

# Tellegen Theorem 2

$$\begin{bmatrix} i_{Q1} \\ \vdots \\ i_{Q10} \end{bmatrix} = \begin{bmatrix} y_{T_{1,1}} & \cdots & y_{T_{1,1}0} \\ \vdots & \ddots & \vdots \\ y_{T_{10,1}} & \cdots & y_{T_{10,10}} \end{bmatrix} \begin{bmatrix} v_1 \\ \vdots \\ v_{10} \end{bmatrix}$$

Solve equation system for the voltages using Gauss algorithm



Voltage transformation factor



One single noise source at input, one single at output



$$[T]^{(y \rightarrow a)} = \begin{bmatrix} 0 & -\frac{1}{y_{2 \times 2_{21}}} \\ 1 & -\frac{y_{2 \times 2_{11}}}{y_{2 \times 2_{21}}} \end{bmatrix}$$



1 current, 1 voltage source at output

# Correlation matrix

$$F = 1 - \frac{T_{\text{sim}}}{T_0} \frac{|y_{\underline{G}}|^2 C_{11}^{(a)} + C_{22}^{(a)} + 2\Re\{y_{\underline{G}} C_{12}^a\}}{g_G}$$

$$R_n = \frac{T_{\text{sim}}}{T_0} C_{11}^a$$

Correlation matrix

$$[C]^{(a)} = [T]^{(y \rightarrow a)} [C]^{(y)} [T]^{(y \rightarrow a)^+}$$

$$V_{\text{NF}} [\text{dBm} / \sqrt{\text{Hz}}] =$$

$$20 \log \left( \sqrt{\frac{T_{\text{sim}}}{T_0} \cdot i_0 i_0^* \frac{50\Omega}{50\Omega \Re(y_{2 \times 2, 22}) + 1}} \cdot 1000 \right)$$

$$\Gamma_{G_{\text{opt}}} = \frac{1 - y_{\underline{G}_{\text{opt}}} Z_0}{1 + y_{\underline{G}_{\text{opt}}} Z_0}$$



# Verification 1

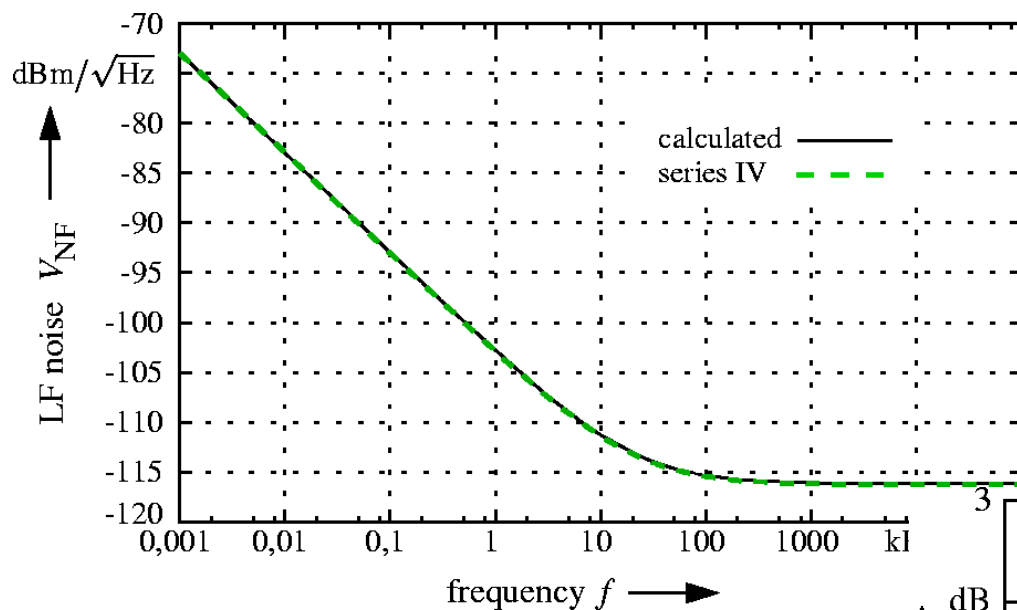


Fig.: Calculation for  $1/f$ -noise. Comparison of proposed algorithm versus series IV simulation.

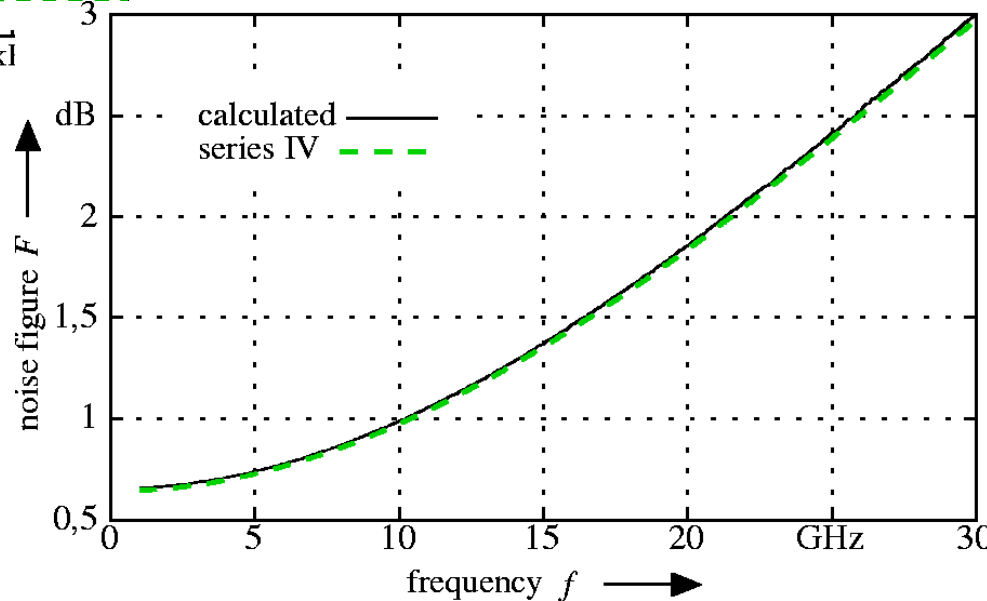
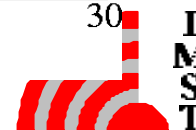


Fig.: Calculation of noise figure  $F$ . Comparison of proposed algorithm versus series IV simulation.



# Verification 2

Fig.: Simulation and measurement of minimum noise figure.

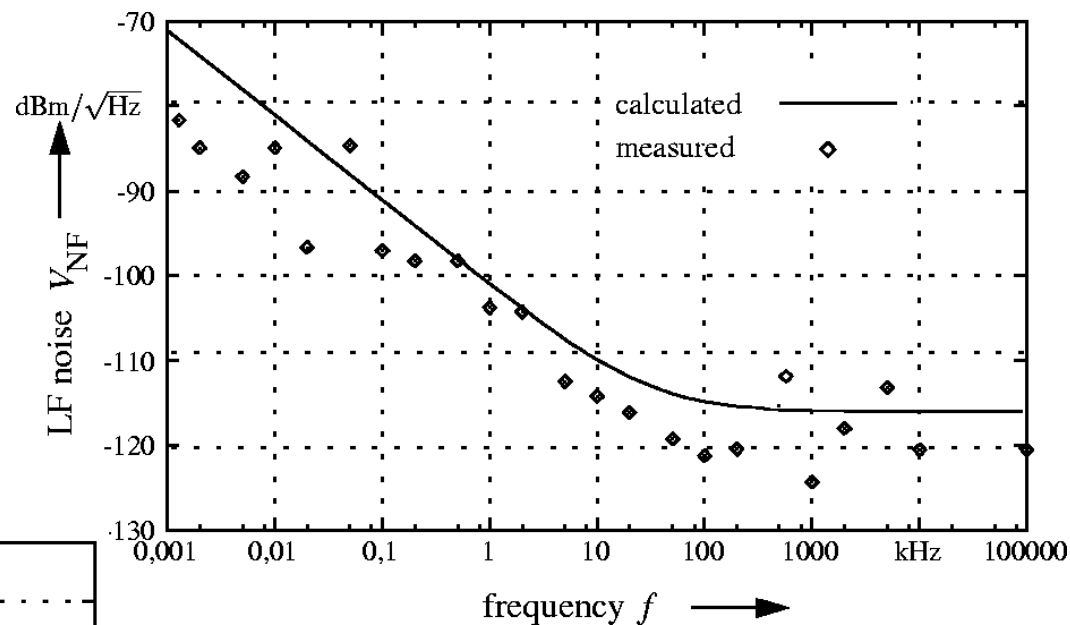
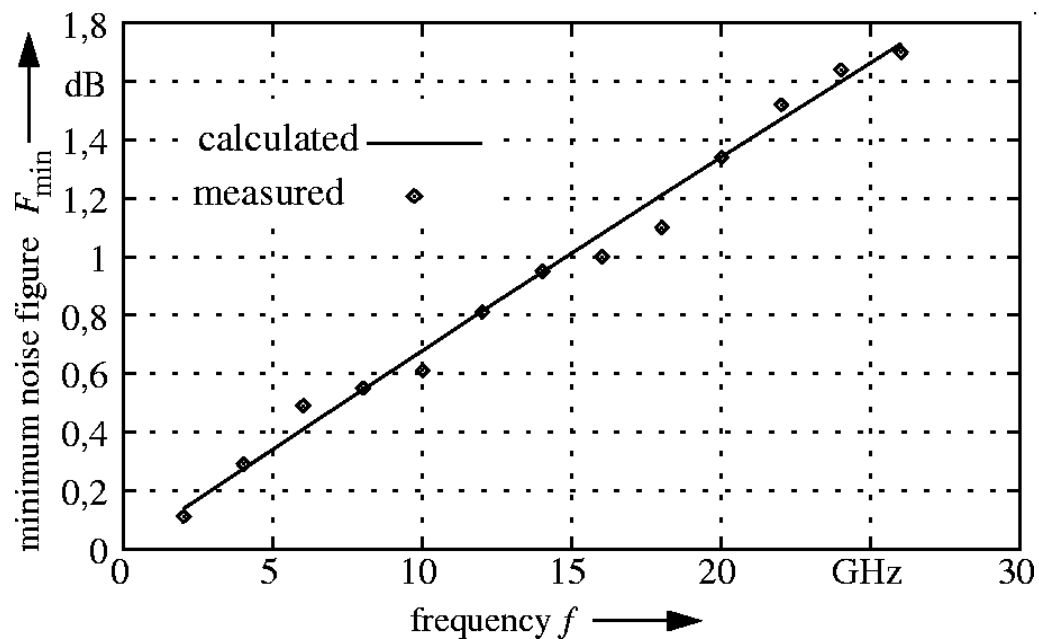


Fig.: Simulation and measurement of 1/f-noise.

# Verification 2

1/f-noise parameter extraction

$$i_f^2 = k_f \frac{I^{af}}{f^b} \Delta f$$

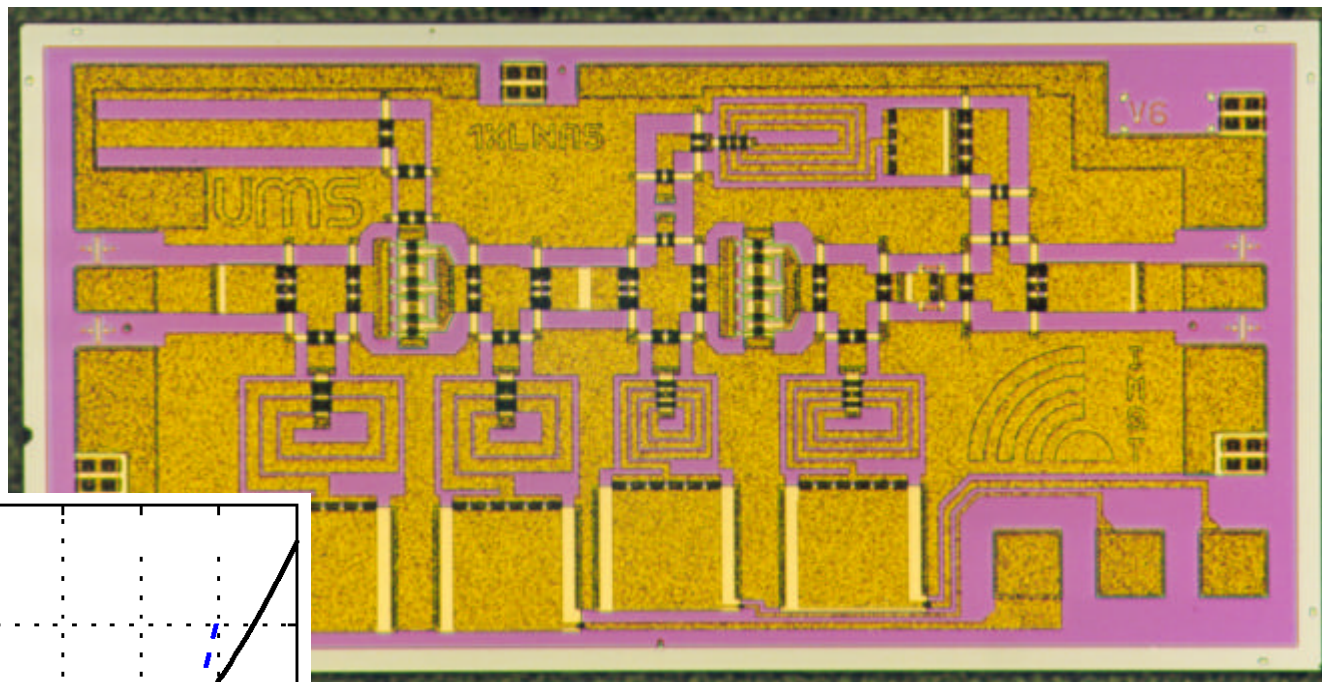


Fig.: Chip photography of the X-band LNA.

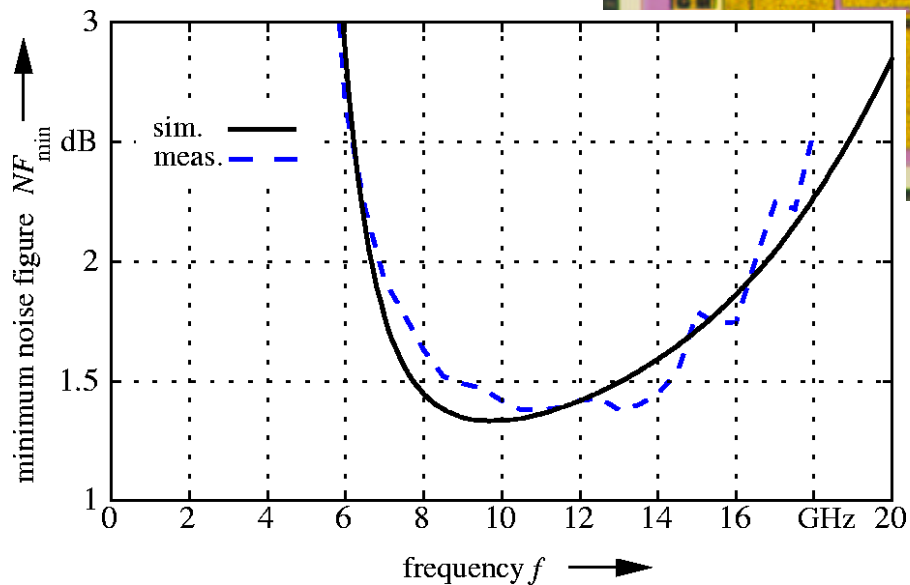


Fig.: Minimum noise figure. Measurement versus simulation.



# Conclusion

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- Fast noise calculation method
- Excellent comparison to commercial available methods (ADS)
- Allows simulation as well as extraction
- LF and RF noise behaviour